# IPB120N04S3-02 IPI120N04S3-02, IPP120N04S3-02

| Parameter                                      | Symbol              | Conditions                                   | Values |      |      | Unit |
|--|---------------------|--|--------|------|------|------|
|  |                     |  | min.   | typ. | max. | 1    |
| Thermal characteristics <sup>2)</sup>          |                     |  |        |      |      |      |
| Thermal resistance, junction - case            | R <sub>thJC</sub>   |  | -      | -    | 0.5  | K/W  |
| Thermal resistance, junction - ambient, leaded | $R_{ m thJA}$       |  | -      | -    | 62   |      |
| SMD version, device on PCB                     | $R_{\mathrm{thJA}}$ | minimal footprint                            | -      | -    | 62   |      |
|  |                     | 6 cm <sup>2</sup> cooling area <sup>3)</sup> | -      | -    | 40   |      |

# **Electrical characteristics,** at $T_{\rm j}$ =25 °C, unless otherwise specified

#### **Static characteristics**

| Drain-source breakdown voltage   | V <sub>(BR)DSS</sub> | V <sub>GS</sub> =0 V, I <sub>D</sub> = 1 mA                              | 40  | -    | -   | V  |
|----------------------------------|----------------------|--|-----|------|-----|----|
| Gate threshold voltage           | $V_{\rm GS(th)}$     | V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =230 μA                | 2.1 | 3.0  | 4.0 | ]  |
| Zero gate voltage drain current  | I <sub>DSS</sub>     | V <sub>DS</sub> =40 V, V <sub>GS</sub> =0 V,<br>T <sub>j</sub> =25 °C    | 1   | 1    | 1   | μΑ |
|                                  |                      | $V_{\rm DS}$ =40 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =125 °C <sup>2)</sup> | -   | -    | 100 |    |
| Gate-source leakage current      | I <sub>GSS</sub>     | V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V                              | -   | -    | 100 | nA |
| Drain-source on-state resistance | R <sub>DS(on)</sub>  | V <sub>GS</sub> =10 V, I <sub>D</sub> =80 A                              | -   | 1.65 | 2.3 | mΩ |
|                                  |                      | $V_{\rm GS}$ =10 V, $I_{\rm D}$ =80 A, SMD version                       | -   | 1.35 | 2   |    |



| Parameter                                 | Symbol Conditions    | Conditions   | Values |       |       | Unit |
|---|----------------------|--|--------|-------|-------|------|
|   |                      |  | min.   | typ.  | max.  |      |
| Dynamic characteristics <sup>2)</sup>     |                      |  |        |       |       |      |
| Input capacitance                         | C iss                | V <sub>GS</sub> =0 V, V <sub>DS</sub> =25 V,<br>f=1 MHz                              | -      | 11000 | 14300 | рF   |
| Output capacitance                        | Coss                 |  | -      | 3000  | 3900  |      |
| Reverse transfer capacitance              | C <sub>rss</sub>     |  | -      | 470   | 710   |      |
| Turn-on delay time                        | t <sub>d(on)</sub>   | $V_{\rm DD}$ =20 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =80 A, $R_{\rm G}$ =1.3 $\Omega$ | -      | 35    | -     | ns   |
| Rise time                                 | t <sub>r</sub>       |  | -      | 19    | -     |      |
| Turn-off delay time                       | t <sub>d(off)</sub>  |  | -      | 57    | -     |      |
| Fall time                                 | t <sub>f</sub>       |  | -      | 18    | -     |      |
| Gate Charge Characteristics <sup>2)</sup> |                      |  |        | T     | Γ     | ı    |
| Gate to source charge                     | Q <sub>gs</sub>      | V <sub>DD</sub> =32 V, I <sub>D</sub> =80 A,<br>V <sub>GS</sub> =0 to 10 V           | -      | 54    | 70    | nC   |
| Gate to drain charge                      | Q <sub>gd</sub>      |  | -      | 38    | 67    |      |
| Gate charge total                         | $Q_g$                |  | -      | 160   | 210   |      |
| Gate plateau voltage                      | V <sub>plateau</sub> |  | -      | 5     | -     | V    |
| Reverse Diode <sup>2)</sup>               |                      |  |        |       |       |      |
| Diode continous forward current           | Is                   | - T <sub>C</sub> =25 °C  | -      | -     | 120   | Α    |
| Diode pulse current                       | I <sub>S,pulse</sub> |  | -      | -     | 480   |      |
| Diode forward voltage                     | V <sub>SD</sub>      | V <sub>GS</sub> =0 V, I <sub>F</sub> =80 A,<br>T <sub>j</sub> =25 °C                 | -      | 0.83  | 1.2   | V    |
| Reverse recovery time                     | t <sub>rr</sub>      | $V_{R}$ =20 V, $I_{F}$ = $I_{S}$ , $di_{F}/dt$ =100 A/µs                             | -      | 70    | -     | ns   |
| Reverse recovery charge                   | Q <sub>rr</sub>      |  | -      | 145   | -     | nC   |

<sup>&</sup>lt;sup>1)</sup> Current is limited by bondwire; with an  $R_{thJC}$  = 0.5 K/W the chip is able to carry 306 A at 25°C. For detailed information see Application Note ANPS071E at www.infineon.com/optimos

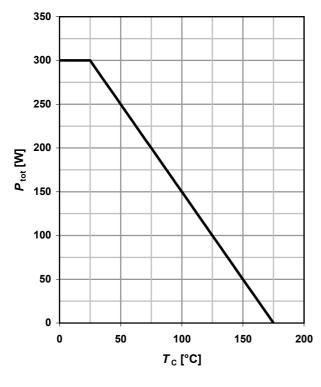
<sup>&</sup>lt;sup>2)</sup> Defined by design. Not subject to production test.

 $<sup>^{3)}</sup>$  Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm $^{2}$  (one layer, 70  $\mu$ m thick) copper area for drain connection. PCB is vertical in still air.



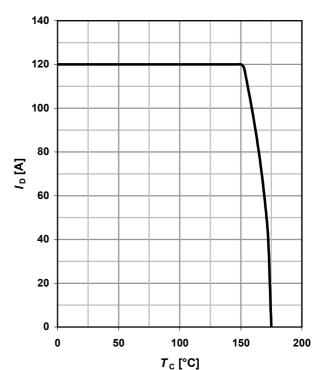
#### 1 Power dissipation

$$P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} \ge 6 \text{ V}$$



#### 2 Drain current

$$I_D = f(T_C); V_{GS} \ge 6 \text{ V}$$



#### 3 Safe operating area

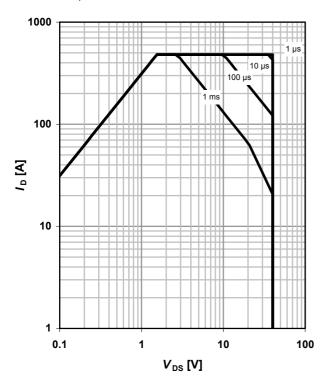
$$I_D = f(V_{DS}); T_C = 25 \,^{\circ}\text{C}; D = 0; \text{SMD}$$

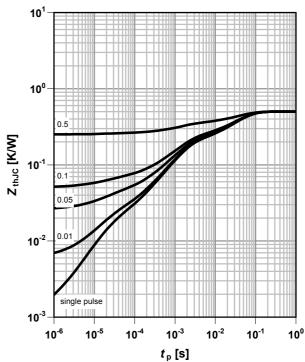
parameter:  $t_p$ 

#### 4 Max. transient thermal impedance

$$Z_{thJC} = f(t_p)$$

parameter:  $D = t_p/T$ 







## 5 Typ. output characteristics

 $I_D = f(V_{DS}); T_j = 25 °C; SMD$ 

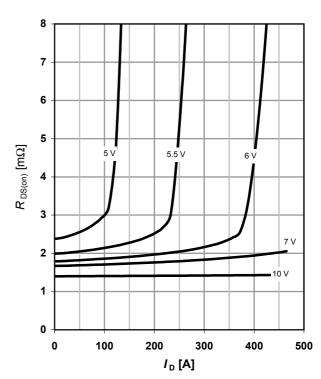
parameter:  $V_{\rm GS}$ 

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#### 6 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(I_D); T_j = 25 \text{ °C}; SMD$ 

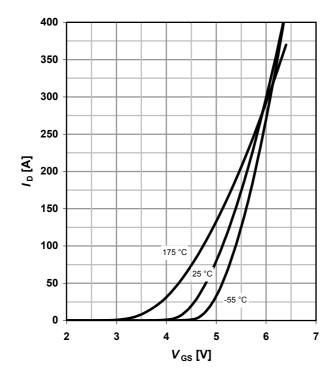
parameter: V<sub>GS</sub>



#### 7 Typ. transfer characteristics

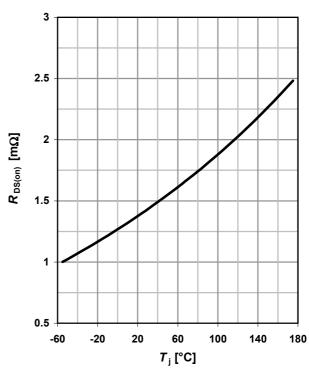
 $I_D = f(V_{GS}); V_{DS} = 6V$ 

parameter: T<sub>i</sub>



#### 8 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(T_j); I_D = 80 \text{ A}; V_{GS} = 10 \text{ V}; \text{SMD}$ 





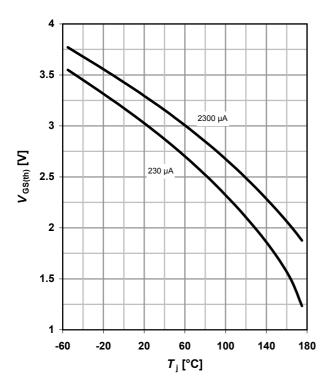
## 9 Typ. gate threshold voltage

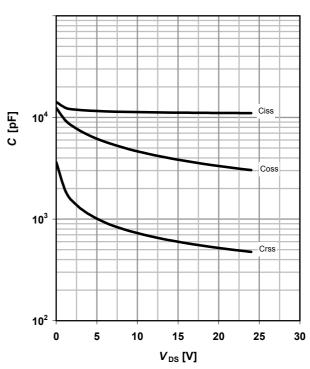
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$ 

parameter:  $I_D$ 

#### 10 Typ. capacitances

 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$ 





#### 11 Typical forward diode characteristicis

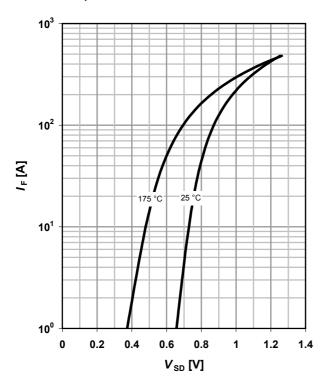
 $IF = f(V_{SD})$ 

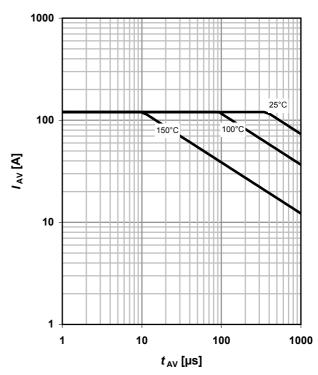
parameter: T<sub>i</sub>

#### 12 Typ. avalanche characteristics

 $I_{AS} = f(t_{AV})$ 

parameter: T<sub>j(start)</sub>







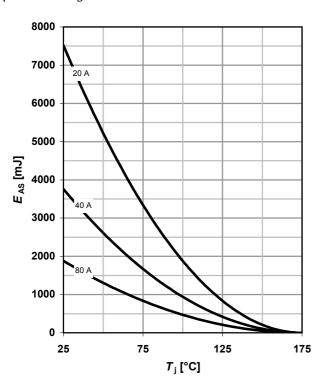
## 13 Typical avalanche energy

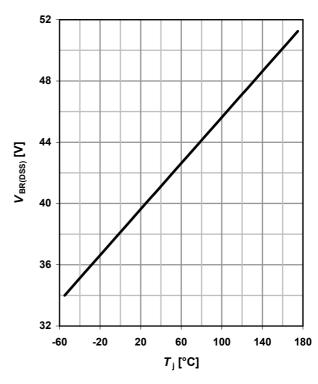
## $E_{AS} = f(T_i)$

parameter:  $I_{\rm D}$ 

#### 14 Typ. drain-source breakdown voltage

$$V_{BR(DSS)} = f(T_i); I_D = 1 \text{ mA}$$

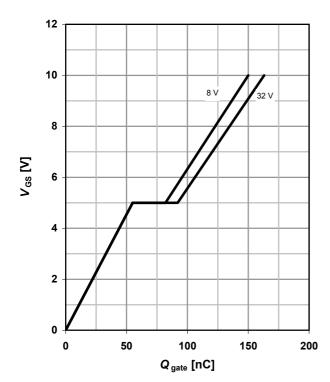




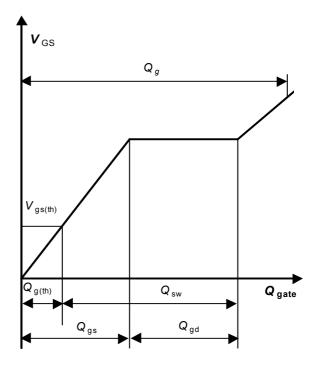
## 15 Typ. gate charge

 $V_{\rm GS}$  = f( $Q_{\rm gate}$ );  $I_{\rm D}$  = 80 A pulsed

parameter: V<sub>DD</sub>



#### 16 Gate charge waveforms





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# IPB120N04S3-02 IPI120N04S3-02, IPP120N04S3-02

Revision History

| Version | Date | Changes |
|---------|------|---------|
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